eGaN® FET DATASHEET EPC2307

EPC2307 – Enhancement Mode Power Transistor

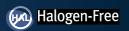
 V_{DS} , 200 V $R_{DS(on)}$, $10\,m\Omega$ max











Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R_{DS(on)}, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR}. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Q	u	es	iti	0	n	s:	
	П	•	П	7			



	Maximum Ratings					
	PARAMETER	VALUE	UNIT			
\ \/	Drain-to-Source Voltage (Continuous)	200	V			
V _{DS}	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	240	V			
I _D	Continuous (T _A = 25°C)	48				
	Pulsed (25°C, T _{PULSE} = 300 μs)	130	A			
.,	Gate-to-Source Voltage	6				
V _{GS}	Gate-to-Source Voltage	-4	V			
TJ	Operating Temperature	-40 to 150)			
T _{STG}	Storage Temperature	-40 to 150				

	Static Characteristics ($T_J = 25^{\circ}$ C unless otherwise stated)							
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_D = [TBD]$	200			٧		
I _{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 160 \text{ V}$		0.002				
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.006		mA		
I _{GSS}	Gate-to-Source Forward Leakage#	$V_{GS} = 5 \text{ V}, T_J = 125^{\circ}\text{C}$		0.4		IIIA		
	Gate-to-Source Reverse Leakage	V _{GS} = -4 V		0.002				
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 4 \text{ mA}$	0.8	1.1	2.5	V		
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 16 \text{ A}$		8.2	10	mΩ		
V_{SD}	Source-Drain Forward Voltage#	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.6		V		

[#] Defined by design. Not subject to production test.



Package size: 3 x 5 mm

Applications

- · Synchronous Rectification
- AC/DC chargers, SMPS, adaptors
- High Frequency DC-DC Conversion
- · Class D audio
- · Wireless Power
- · High power lidar & dToF

Benefits

- Higher Efficiency Lower conduction and switching losses, zero reverse recovery losses
- Ultra Small Footprint Higher power density

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2307

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	Dynamic Characteristics [#] (T _J = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT	
C _{ISS}	Input Capacitance			1401			
C _{RSS}	Reverse Transfer Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		1.2			
C _{OSS}	Output Capacitance			326		pF	
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 1)	V 0+- 100VVV 0V		445			
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 2)	$V_{DS} = 0$ to 100 V, $V_{GS} = 0$ V		579			
Q_{G}	Total Gate Charge	$V_{DS} = 100 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 16 \text{ A}$		10.6			
Q _{GD}	Gate-to-Drain Charge	V _{DS} = 100 V, I _D = 16 A 1.3					
Qoss	Output Charge	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		58		nC	
Q _{RR}	Source-Drain Recovery Charge			0			

All measurements were done with substrate shorted to source.

Note 1: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}. Note 2: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C

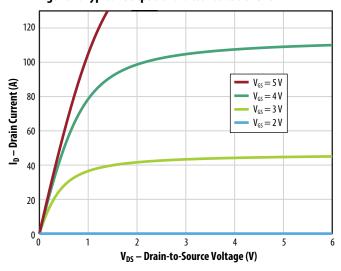


Figure 2: Typical Transfer Characteristics

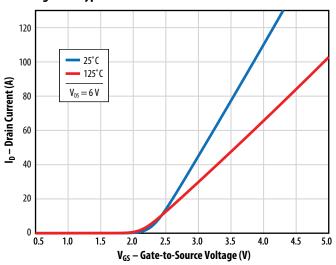


Figure 3: Typical R_{DS(on)} vs. V_{GS} for Various Drain Currents

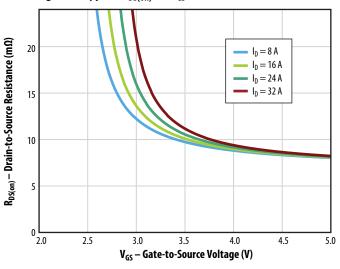
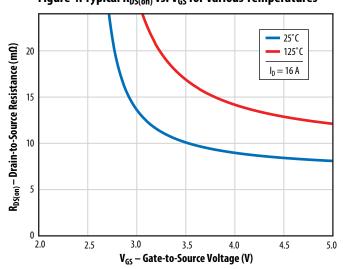


Figure 4: Typical R_{DS(on)} vs. V_{GS} for Various Temperatures



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Figure 5a: Typical Capacitance (Linear Scale)

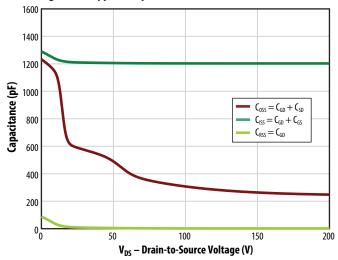


Figure 5b: Typical Capacitance (Log Scale)

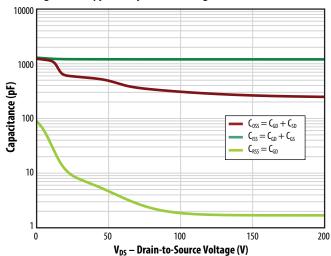


Figure 6: Typical Output Charge and Coss Stored Energy

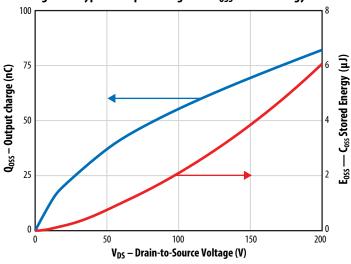


Figure 7: Typical Gate Charge

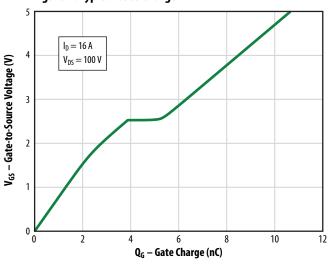


Figure 8: Typical Reverse Drain-Source Characteristics

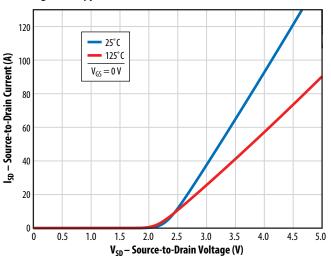
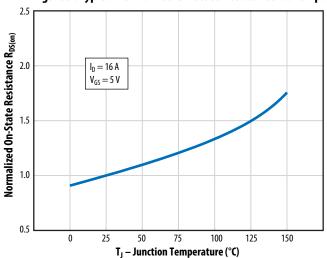


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage.

EPC recommends 0 V for OFF.

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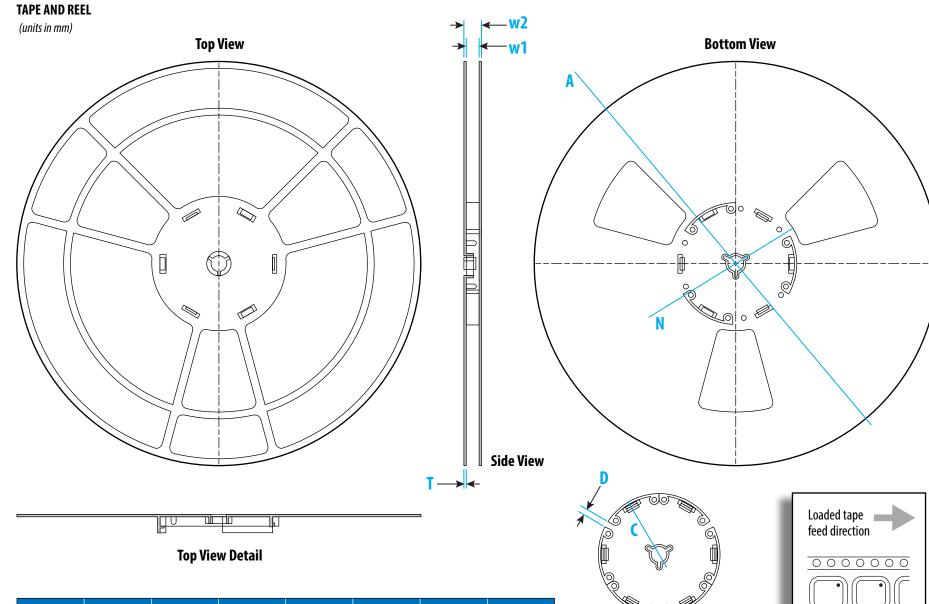
1.3 $I_D = 4 \text{ mA}$ **Normalized Threshold Voltage** 1.2 0.7 75 100 125 150

T_J – Junction Temperature (°C)

Figure 10: Typical Normalized Threshold Voltage vs. Temp.

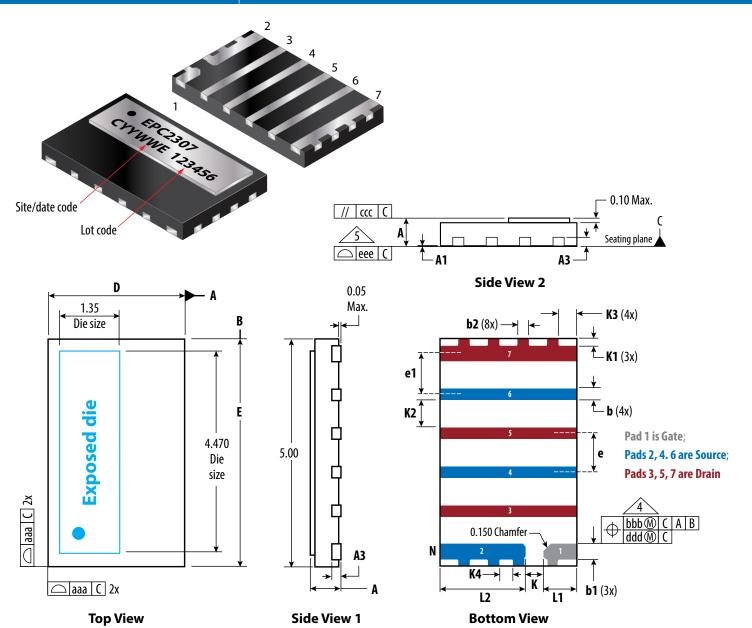
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Bottom View Detail



Туре	A	N	C	D	w1	w2	T
8MM	Ø330±2	Ø100±2	Ø13.1±0.2	5.6±0.5	8.4+1.5	14.4	2.1±0.5
12MM	Ø330±2	Ø100±2	Ø13.1±0.2	5.6±0.5	12.4+1.5	18.4	2.1±0.5
16MM	Ø330±2	Ø100±2	Ø13.1±0.2	5.6±0.5	16.4+1.5	22.4	2.1±0.5
24MM	Ø330±2	Ø100±2	Ø13.1±0.2	5.6±0.5	24.4+1.5	30,4	2.1±0.5

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SYMBOL		Dimension (mm)						
STMDUL	MIN	Nominal	MAX	Note				
Α	0.60	0.65	0.70					
A1	0.00	0.02	0.05					
А3		0.20 Ref						
b	0.20	0.25	0.30	4				
b1	0.30	0.35	0.40	4				
b2	0.20	0.25	0.30	4				
D		3.00 BSC						
E		5.00 BSC						
e		0.85 BSC						
e1		0.90 BSC						
L1	0.625	0.725	0.825					
L2	1.775	1.875	1.975					

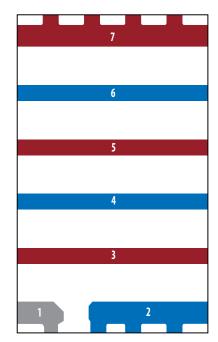
SYMBOL		Dimension	(mm)					
STMBUL	MIN	Nominal	MAX	Note				
K	0.35	0.40	0.45					
K1	0.10	0.15	0.20					
K2	0.55	0.60	0.65					
К3	0.35	0.40	0.45					
K4	0.25	0.30	0.35					
aaa		0.05						
bbb		0.10						
ССС		0.10						
ddd		0.05						
eee		0.08						
N		15		3				
NE		6						

Notes:

- 1. Dimensioning and tolerancing conform to ASME Y14.5-2009
- 2. All dimensions are in millimeters
- 3. **N** is the total number of terminals
- A. Dimension **b** applies to the metallized terminal. If the terminal has a radius on the other end of it, dimension **b** should not be measured in that radius area.
- 5. Coplanarity applies to the terminals and all the other bottom surface metallization.

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TRANSPARENT VIEW

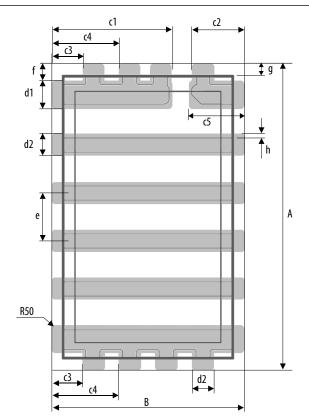


PIN	DESCRIPTION	
1	Gate	
2	Source	
3	Drain	
4	Source	
5	Drain	
6	Source	
7	Drain	

Transparent Top View

RECOMMENDED LAND PATTERN





Land pattern is solder mask defined.

DIM	Nominal
A	5.4
В	3.4
c1	2.1
c2	0.90
c3	0.55
c4	1.20
c5	0.975
d1	0.45
d2	0.35
e	0.85
f	0.30
g	0.2
h	0.05

Additional resources available:

- Assembly resources https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf
- Library of Altium footprints for production FETs and ICs https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip (for preliminary device Altium footprints, contact EPC)

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